

LMP3825EAF 30V P-Channel MOSFET

Features

- -30V/-0.19A, $R_{DS(ON)}$ <2500m Ω @ V_{GS} =-4.5V
- Low-Voltage Operation
- High-Speed Circuits
- ESD Protection
- SOT-723 package design

Product Description

LMP3825EAF, P-Channel enhancement mode MOSFET, uses Advanced Trench Technology to provide excellent

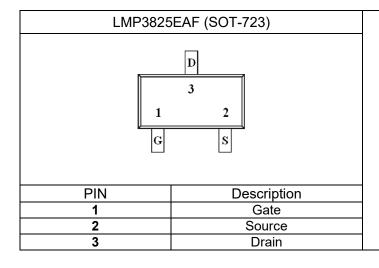
R_{DS(ON)}, low gate charge.

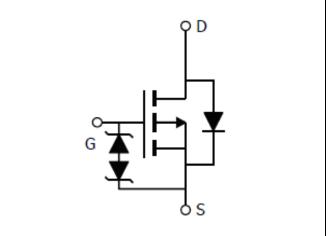
These devices are particularly suited for low voltage power management, such as smart phone and notebook computer, and low in-line power loss are needed in commercial industrial surface mount applications.

Applications

- Drivers, Relays, Solenoids, Lamps, Hammers
- Battery Operated Systems
- Power Supply Converter Circuits
- Load/Power Switching Smart Phones, Pagers

Pin Configuration







Ordering Information

Ordering Information						
Part Number	P/N	PKG code	Pb Free code	Package	Quantity	
LMP3825EAF	LMP3825E	А	F	SOT-723	8000	

Marking Information

Marking Information					
Part Marking	Part Number	LFC code			
5XM	5	XM			

Absolute Maximum Ratings

(T_C=25°C Unless otherwise noted)

Symbol	Parameter	Typical	Unit	
V _{DSS}	Drain-Source Voltage	-30	V	
V _{GSS}	Gate-Source Voltage		±10	V
		T _A =25°C	-0.19	
I_{D}	Continuous Drain Current (TJ=150℃)	T _A =70°C	-0.15	Α
Ірм	Pulsed Drain Current	Pulsed Drain Current		Α
		T _A =25°C	0.15	
P_D	Power Dissipation	T _A =70°C	0.1	W
RеJA	Thermal Resistance Junction to	833	°C/W	
TJ	Operating Junction Temperatu	-55 to +150	°C	
T _{STG}	Storage Temperature Ra	-55 to +150	°C	

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Electrical Characteristics

(T_C=25°C Unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		Static	•			
$V_{(BR)\text{DSS}}$	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =-250uA	-30			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=-250uA$	-0.4		-1.0	V
I _{GSS}	Gate Leakage Current	V _{DS} =0V, V _{GS} =±8V			±10	uA
IDSS	Zero Gate Voltage Drain Current	V _{DS} =-24V, V _{GS} =0V			-1	uA
R _{DS(on)}	Drain-Source On-Resistance	V_{GS} =-4.5V, I_{D} =-0.5A		1.5	2.5	Ω
	Brain-oddice on Resistance	V _{GS} =-2.5V, I _D =-0.2A		1.9	2.9	
		V _{GS} =-1.8V, I _D =-0.1A		2.4	5.0	
g FS	Forward Transconductance	V _{DS} =-10V, I _D =-0.25A		600		mS
V_{SD}	Diode Forward Voltage	I _S =-0.5A, V _{GS} =0V			1.3	V
		Dynamic	•	•		
Qg	Total Gate Charge	V_{DS} =-15V, V_{GS} =-4.5V, I_{D} =-1A		1.0		nC
Qgs	Gate-Source Charge	V _{DS} =-15V, V _{GS} =-8V,		0.2		
Q _{gd}	Gate-Drain Charge	I _D =-1A		0.1		
Ciss	Input Capacitance			54		
Coss	Output Capacitance	V _{DS} =-15V, V _{GS} =0V		10.9		pF
Crss	Reverse Transfer Capacitance	f=1MHz		5.8		
t _{d(on)}	Turn-On Time			3.8		
tr		V_{DD} =-10V, R_L =47 Ω ,		11		ns
t _{d(off)}	Turn-Off Time	I _D ≡-0.2A		45		
t _f		V_{GEN} =-4.5V, R_{G} =10 Ω		20		



Typical Performance Characteristics

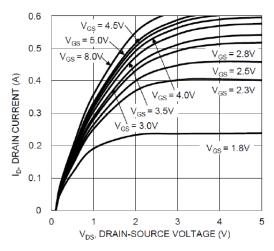


Fig. 1 Typical Output Characteristics

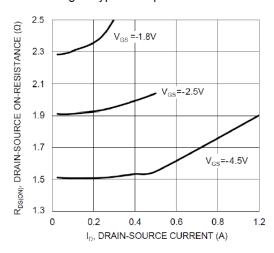


Fig. 3 Typical On-Resistance vs. ID and VGS

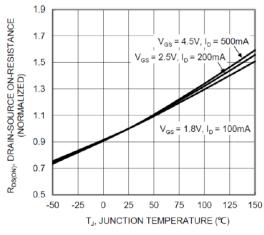


Fig. 5 On-Resistance Variation with TJ

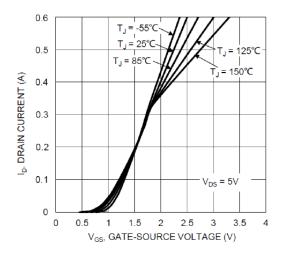


Fig. 2 Typical Transfer Characteristics

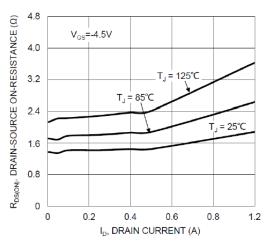


Fig. 4 Typical Drain-Source On-Resistance vs. I_D and T_J

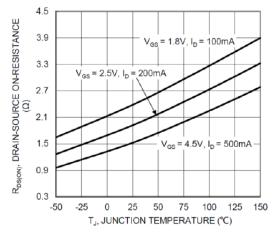
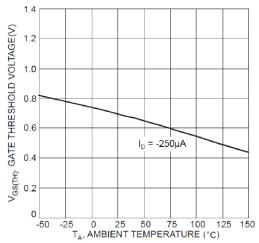


Fig. 6 On-Resistance Variation with TJ



Typical Performance Characteristics(continue)



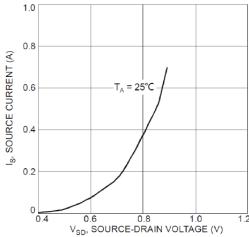


Fig. 7 Gate Threshold Variation vs. TA



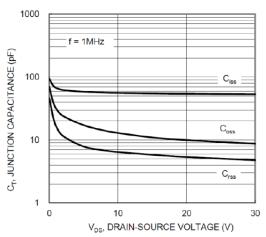


Fig. 8 Diode Forward Voltage vs. Current

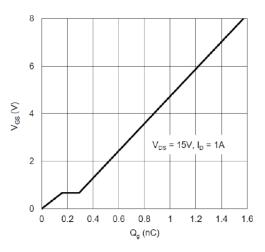


Fig. 9 Typical Capacitance

Fig. 10 Gate Charge

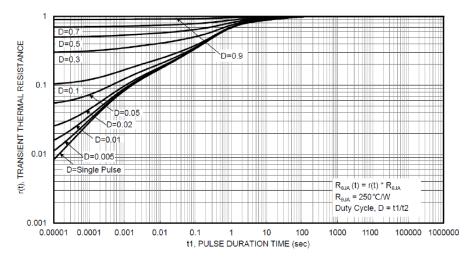
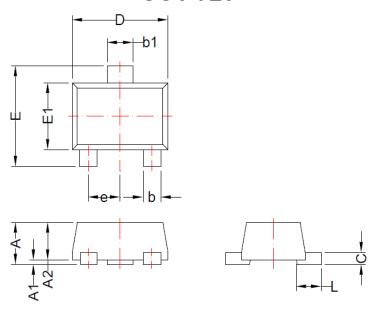


Fig. 11 Transient Thermal Response



Package Dimension:

SOT-723



DIMENSION D DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS.MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL HOT EXCEED 0.25mm PER INTERLEAD FLASH OR PROTRUSIOB SHALL NOT EXCEED 0.25mm PER SIDE.

	Dimensions					
Symbol	Millimeters		Inches			
	Min	Max	Min	Max		
Α	0.45	0.55	0.018	0.022		
A1	0.00	0.10	0.000	0.004		
A2	0.45	0.55	0.018	0.022		
b	0.15	0.30	0.006	0.012		
b1	0.25	0.40	0.010	0.016		
С	0.08	0.20	0.003	0.008		
D	1.10	1.30	0.043	0.051		
E	1.10	1.30	0.043	0.051		
E1	0.70	0.90	0.028	0.035		
е		0.4 BSC		0.016 BSC		
L	0.2	0.42	0.008	0.017		



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